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**(54) DEVICE AND METHOD
FOR ANALYZING SAMPLE
CHIP**

(57) Abstract:

PROBLEM TO BE SOLVED: To provide a device and method for analyzing a sample chip which can make effective the analyzing operation of the sample to be analyzed by detecting with high fidelity and accuracy the fluorescences of different wavelengths at a time from a fluorescent material labeled to the sample which is combined to the sample probe without being affected by excitation light and disturbing light.

SOLUTION: Incident light with a definite thickness is totally reflected by this device for analyzing a sample chip which enables to guide waves and irradiate inside the light from the light source to the end face of the

wave guide plate, to the surface of which many sample probes are fixed. The surface of the wave guide plate to which sample probes are fixed is made image by members for image making. The fluorescent material is excited to make fluorescent by an evanescent wave occurring when the light is totally reflected to guide waves within the wave guide plate with which the sample to be analyzed, for which the fluorescent material is labeled to the sample probe, is coupled to analyze the sample by the fluorescent image of the wave guide plate which is made image.

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